

Error Correction Coding for Flash Memories

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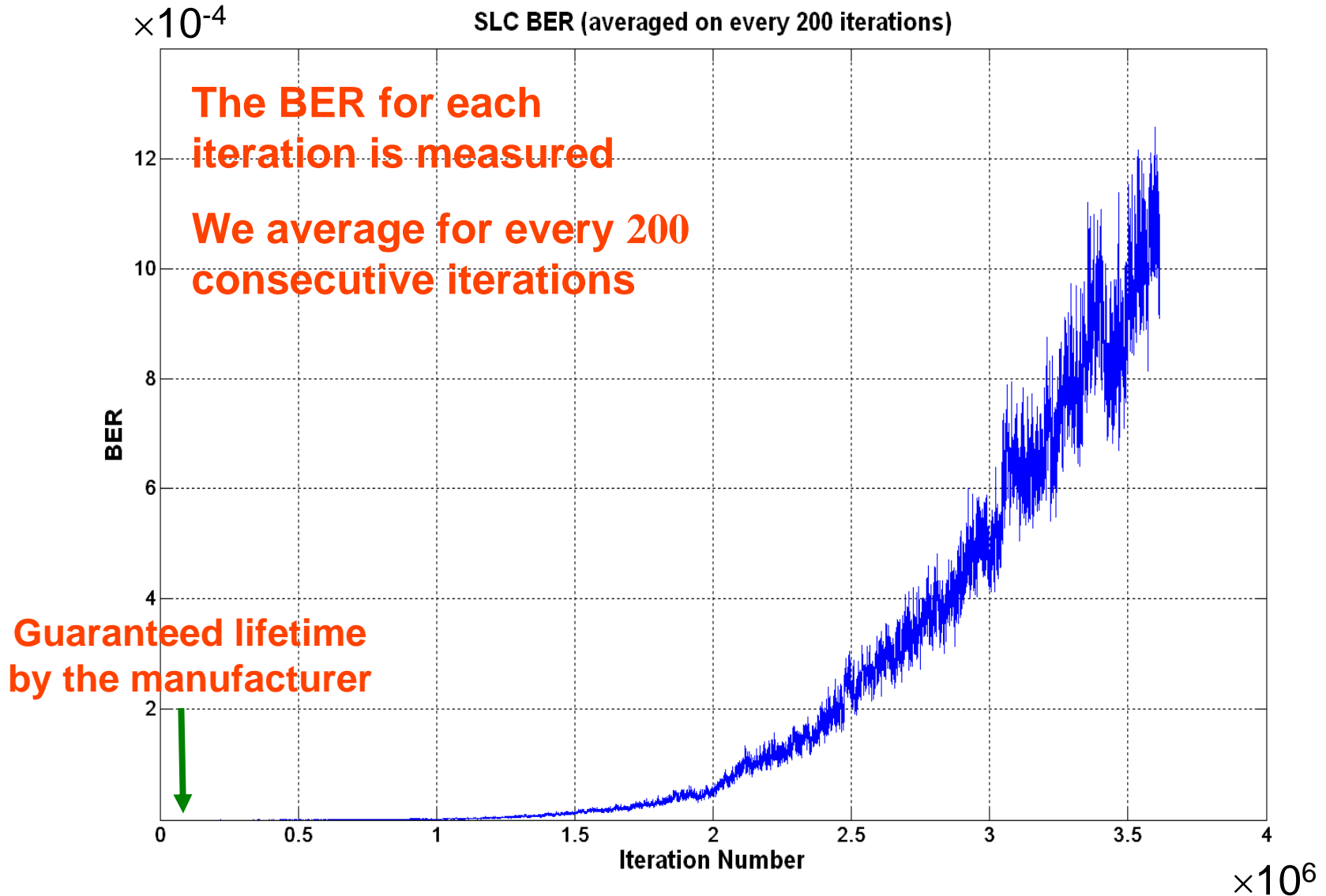


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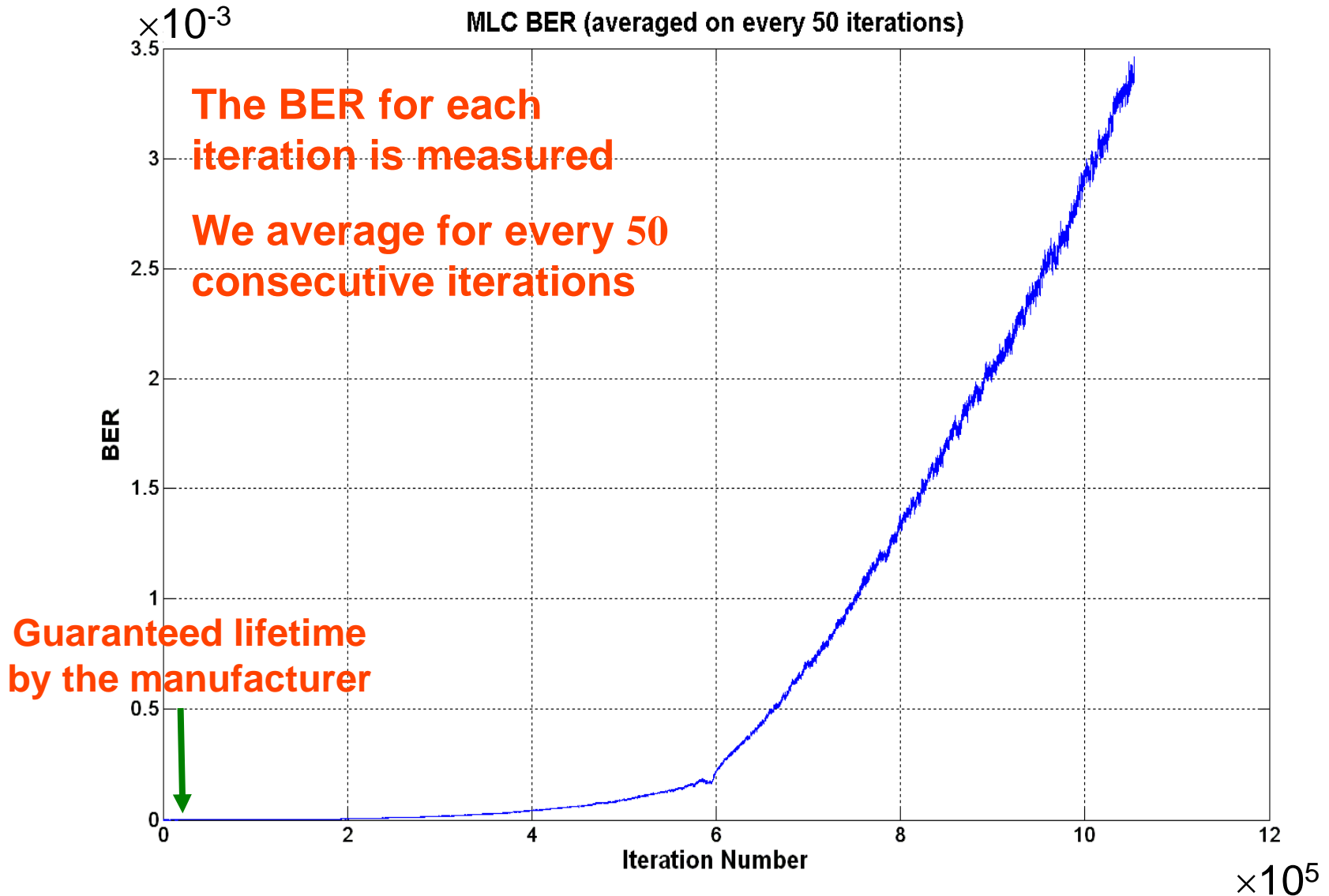
Experiment Description

- We checked several flash memory blocks - **SLC** and **MLC**
- For each block the following steps are repeated
 - The block is **erased**
 - A pseudo-random data is **written** to the block
 - The data is **read** and **compared** to find errors
- Two runs are chosen as representatives for SLC and MLC
 - **SLC** - Collected Iterations: **3,615,224**
 - **MLC** - Collected Iterations: **1,054,031**
- **Remarks:**
 - We measured many more iterations than the manufacturer's guaranteed number of erasures
 - The experiment was done in a lab conditions and related factors such as temperature change, intervals between erasures or multiple readings before erasures were not considered

Raw BER for SLC block



Raw BER for MLC block



Basic Error Characteristic

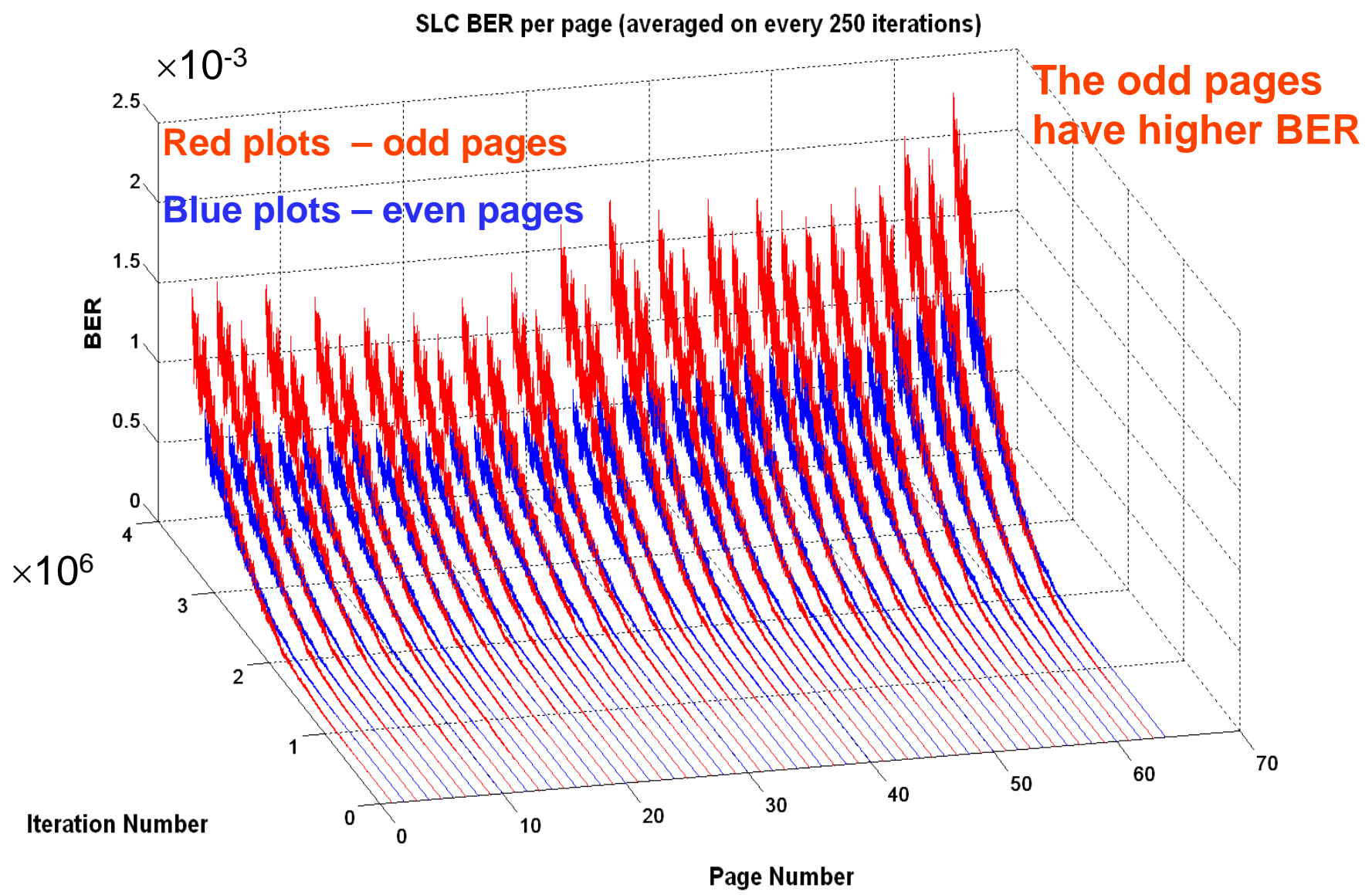
- **Directional Errors** - Number of Plus errors Vs. Minus errors
 - **Plus error**: Cell in state '0' changes to state '1'
 - **Minus error**: Cell in state '1' changes to state '0'
 - We check the distribution of the errors between plus and minus errors and the numbers are the same even for individual bits
 - **Conclusion**: There is no preference to correct more plus than minus errors (or vice versa)
- **Burst behavior**
 - Check how close the errors are to each other
 - Explore the potential (dis)advantage of using a RS code VS a BCH code
 - **Conclusion**: The errors are random and do not have burst pattern behavior

SLC - BER Page Dependency

- We checked the BER for each page **independently**
- SLC block cells layout:
 32×2^{15} cells; each page has 2^{14} cells

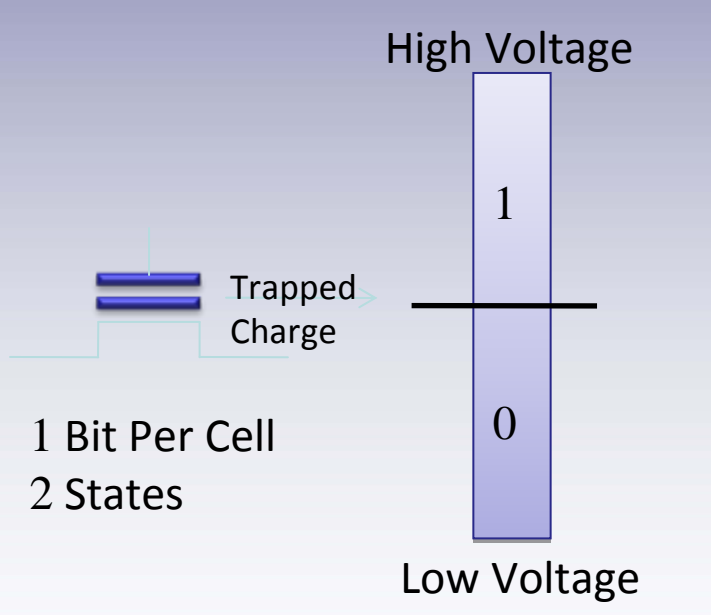
| | |
|---------|---------|
| page 1 | page 2 |
| page 3 | page 4 |
| page 5 | page 6 |
| . | . |
| . | . |
| . | . |
| page 63 | page 64 |

SLC - BER Page Dependency

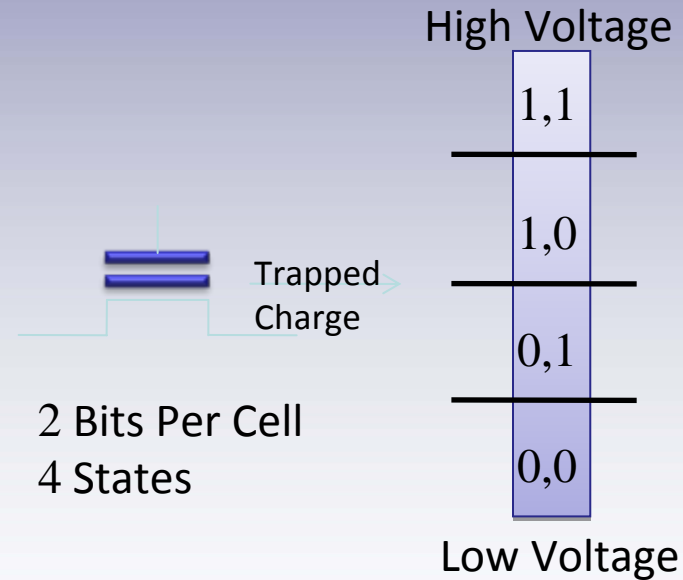


MLC - BER Page Dependency

- The Most Significant Bit (**MSB**) and Least Significant Bit (**LSB**) represented by one cell belong to two different pages
- Pages storing the LSB are less protected from errors



Single Level Cell (SLC)



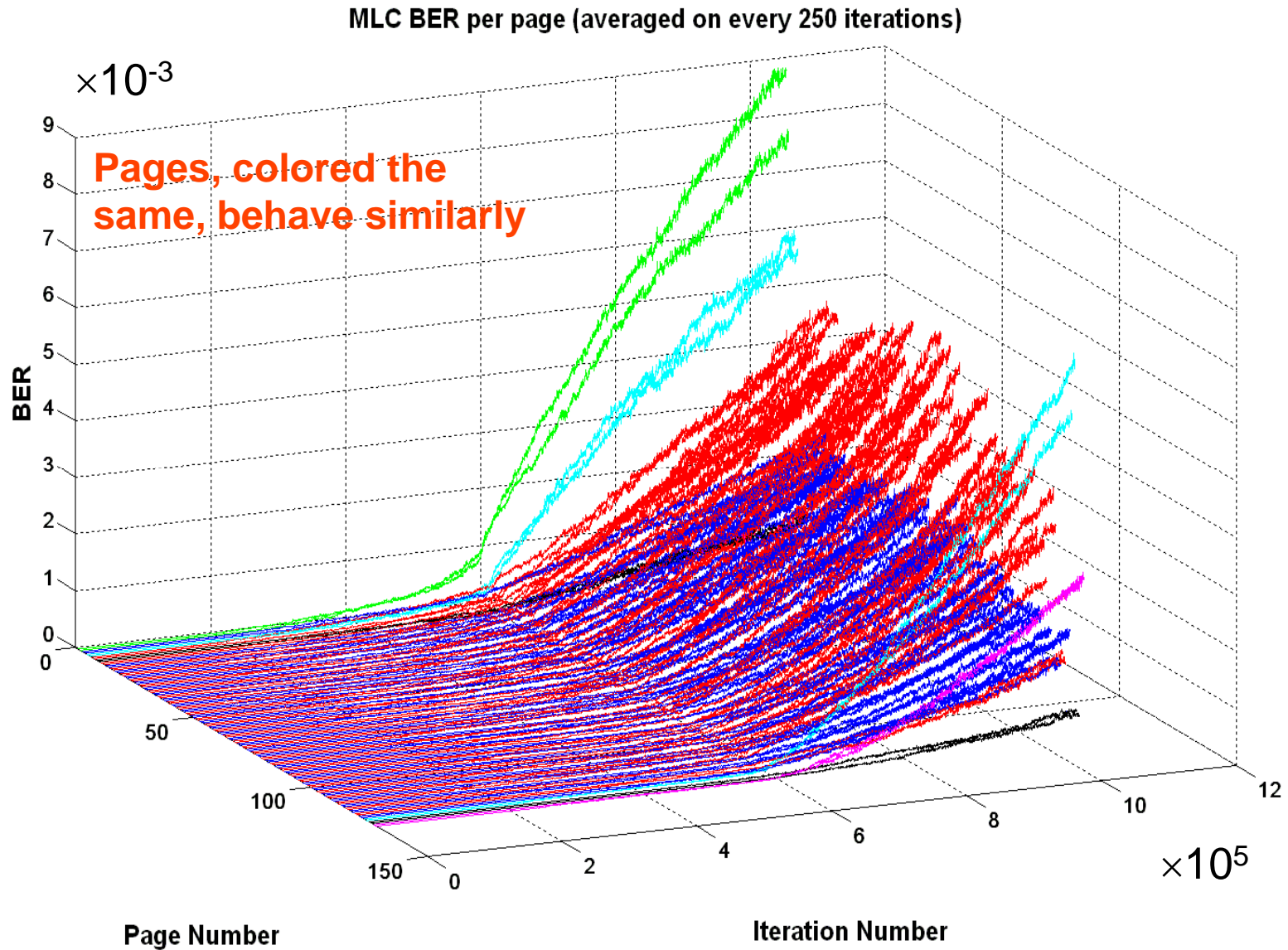
Multi Level Cell (MLC)

MLC - BER Page Dependency

A possible MLC block cell layout:

| Row index | LSB of first 2^{14} cells | MSB of first 2^{14} cells | LSB of last 2^{14} cells | MSB of last 2^{14} cells |
|-----------|-----------------------------|-----------------------------|----------------------------|----------------------------|
| 1 | page 1 | page 5 | page 2 | page 6 |
| 2 | page 3 | page 9 | page 4 | page 10 |
| 3 | page 7 | page 13 | page 8 | page 14 |
| 4 | page 11 | page 17 | page 12 | page 18 |
| 5 | page 15 | page 21 | page 16 | page 22 |
| M | M | M | M | M |
| 31 | page 119 | page 125 | page 120 | page 126 |
| 32 | page 123 | page 127 | page 124 | page 128 |

MLC - BER Page Dependency

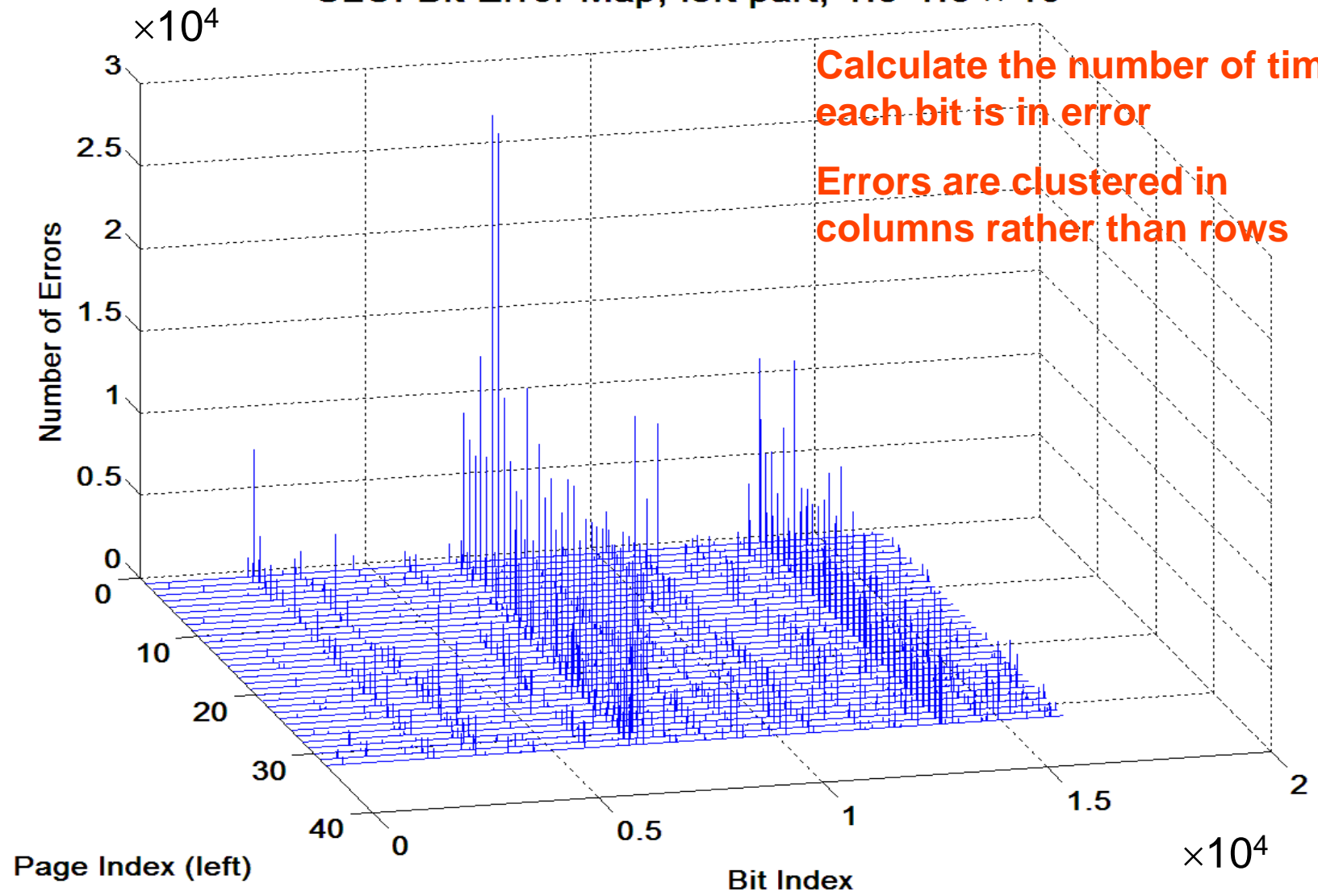


SLC - Bit Error Map

- We checked how the errors behave for each bit
- For a small window of iterations, $1.5-1.6 \times 10^6$ iterations - the BER is roughly fixed, we checked for each bit the number of times it was in error

SLC - Bit Error Map for Odd Pages

SLC: Bit Error Map, left part, $1.5-1.6 \times 10^6$

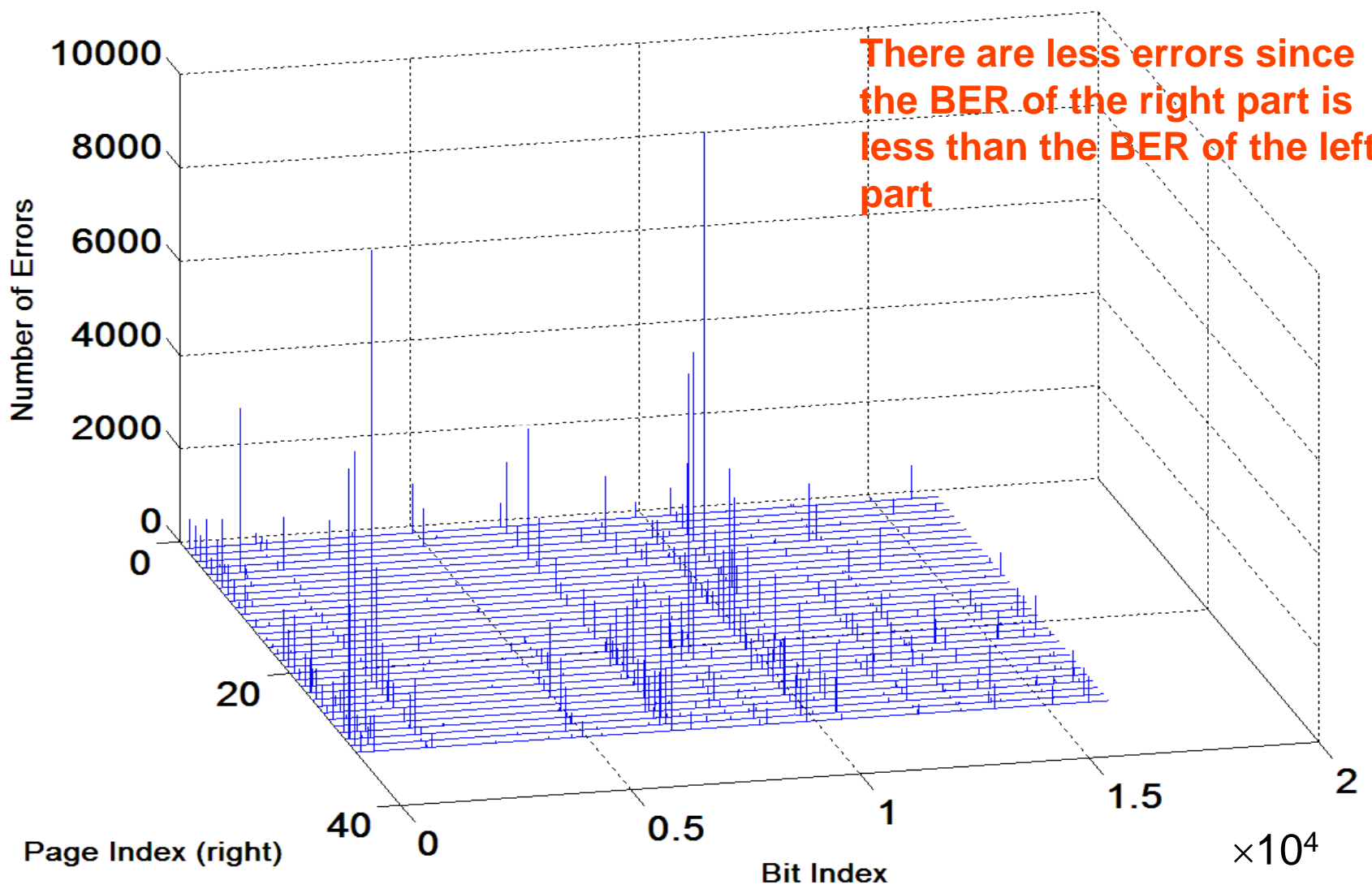


Calculate the number of times each bit is in error

Errors are clustered in columns rather than rows

SLC - Bit Error Map for Even Pages

SLC: Bit Error Map, right part, $1.5-1.6 \times 10^6$



ECC Comparison

- We compare between **BCH**, **RS** and **burst-correcting codes**
- We compute the **BER** and **PER** assuming we used for each of these codes the same number of redundancy bits
- Best results are achieved for **BCH codes**
- We have another scheme for correcting in the entire block in two levels:
 - **First level**: correct and detect errors in each page
 - **Second level**: if there are errors that were detected and not corrected in the pages, use the last redundancy page(s) to correct them
- We could improve the lifetime by **~14%**
Lifetime - first errors occurrence

Write Once Memory (WOM) Codes for SLC



- A scheme for storing two bits twice using only three cells **before erasing the cells**
- The cells only **increase** their level
- How to implement? (in **SLC** block)
 - Each page stores $2\text{KB}/1.5 = 4/3\text{KB}$ per write
 - A page can be written twice before erasing
 - Pages are **encoded** using the **WOM code**
 - When the block has to be rewritten, mark its pages as **invalid**
 - Again write pages using the WOM code **without erasing**
 - **Read before write** at the second write

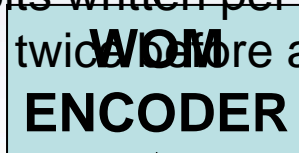
| data | 1 st write | 2 nd write |
|------|-----------------------|-----------------------|
| 00 | 000 | 111 |
| 01 | 100 | 011 |
| 10 | 010 | 101 |
| 11 | 001 | 110 |

Cells state

Advantages:

00.10.00.00.01 ... 00

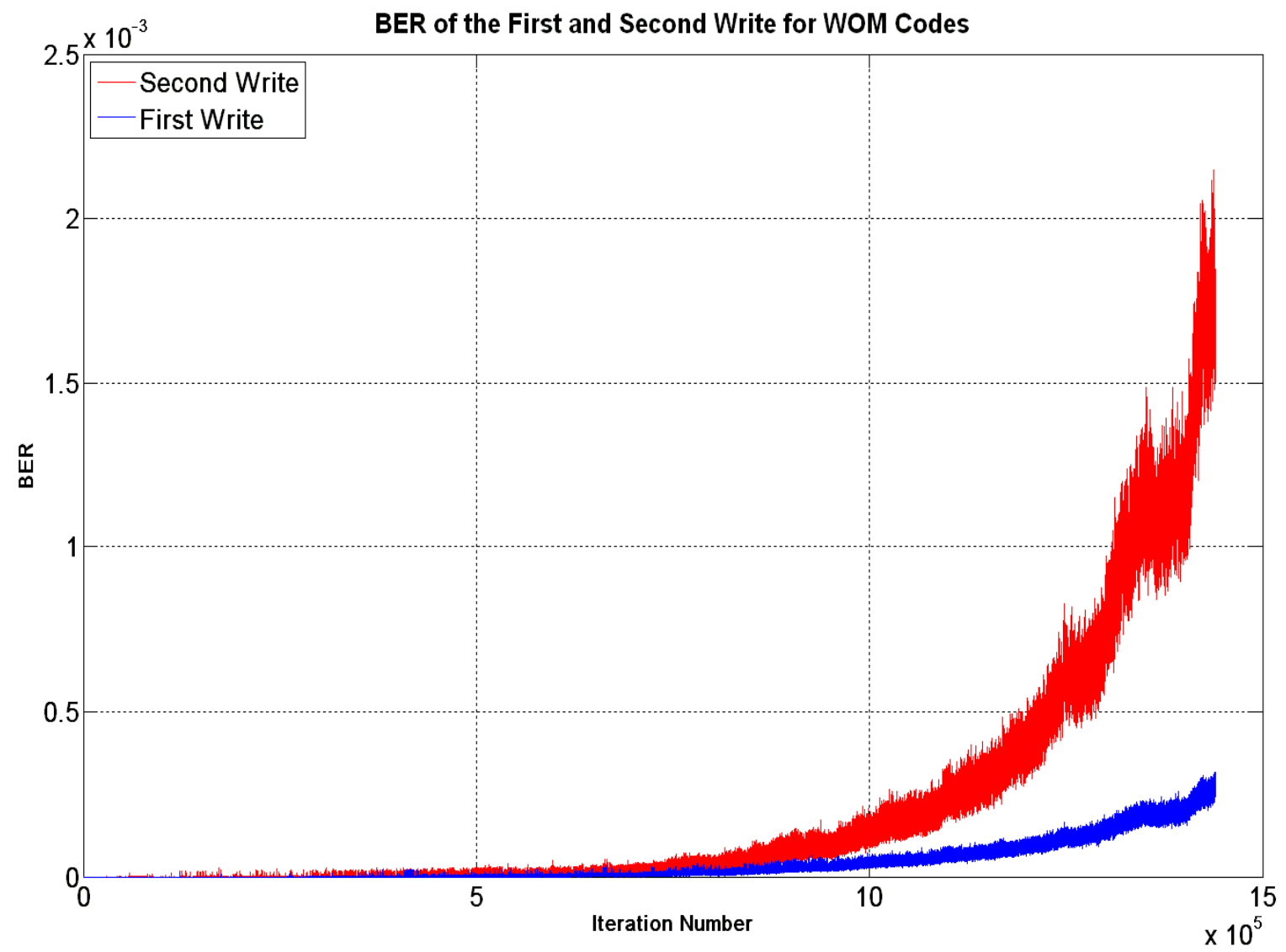
- The number of bits written per cell is **4/3**
- Possible to write twice before a physical erasure



000.000.000.010.001 ... 000



BER for the First and Second Writes



Summary

- Error characterization in flash memories
- Comparison between potential codes
- ECC for the entire block
- Write Once Memory (WOM) codes
- More analysis of codes and error behavior -

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